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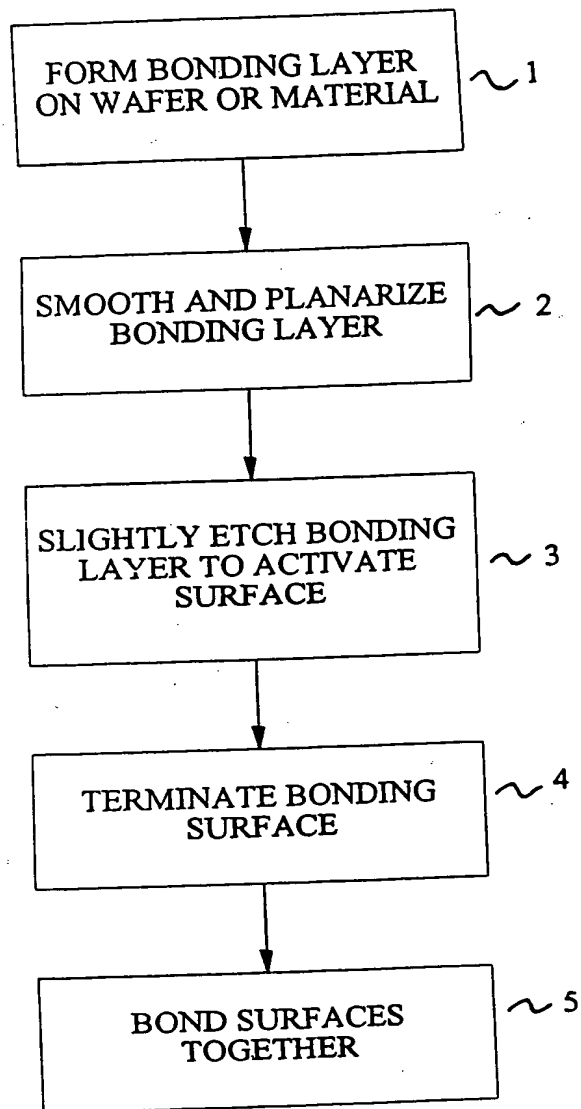


FIG. 1

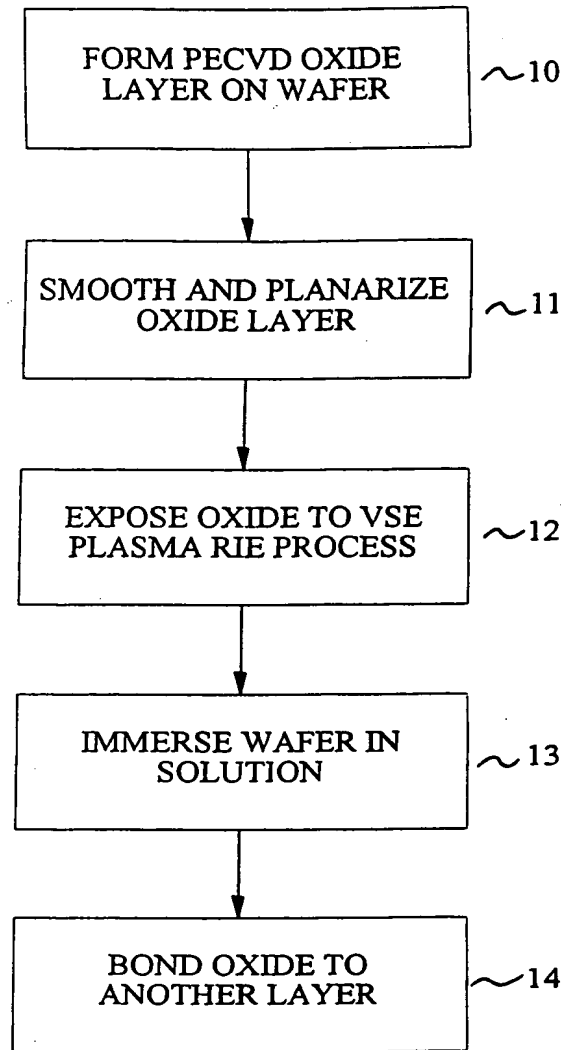


FIG. 2

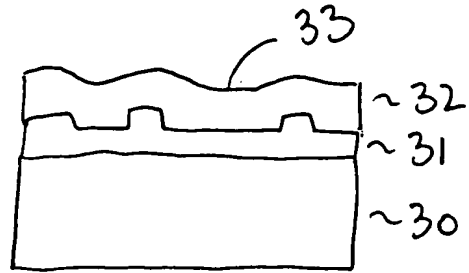


FIG. 3A

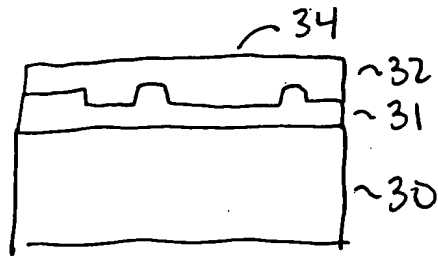


FIG. 3B

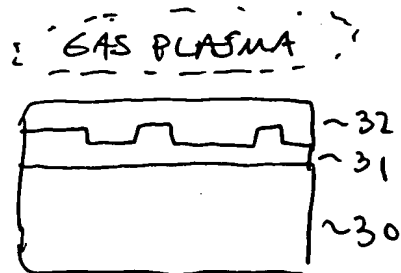


FIG. 3C

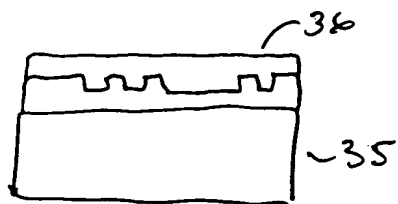


FIG. 3D

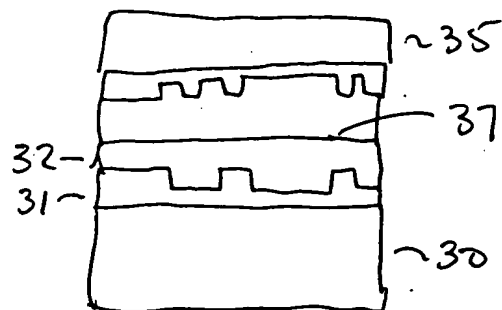
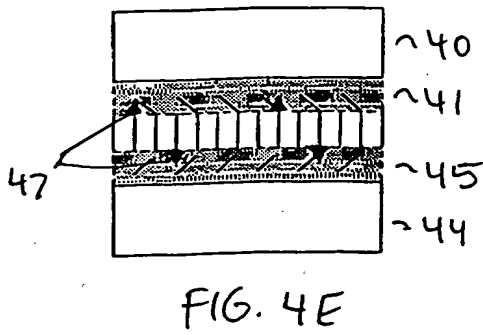
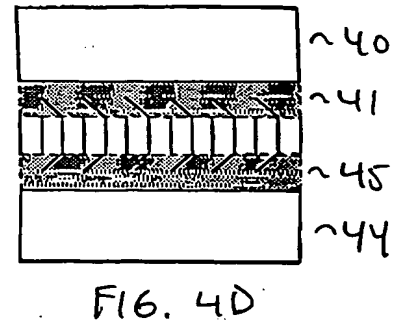
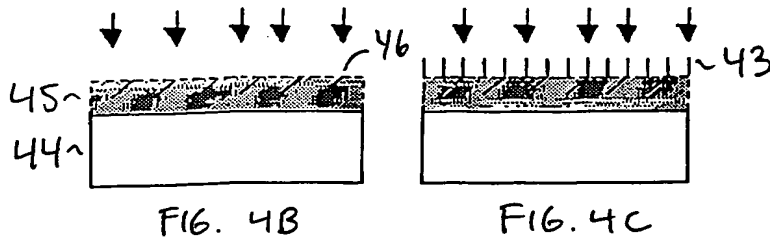
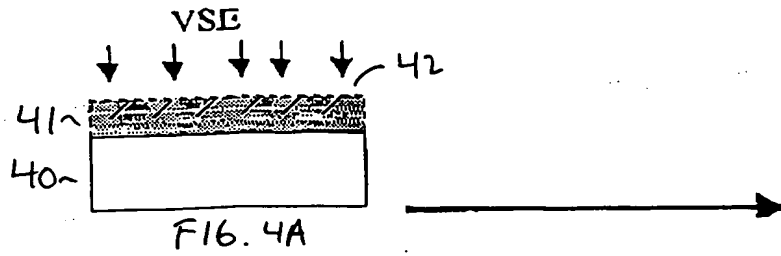
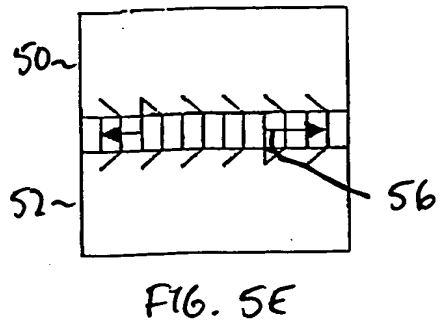
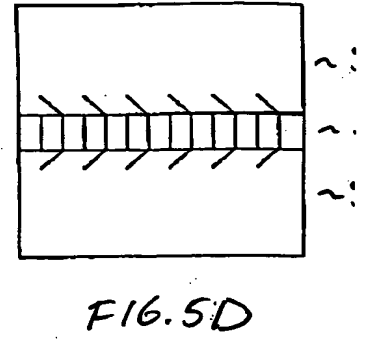
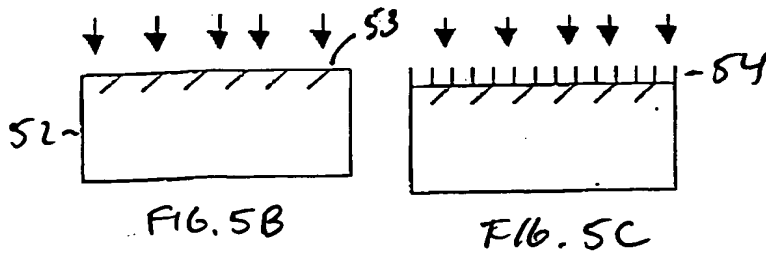
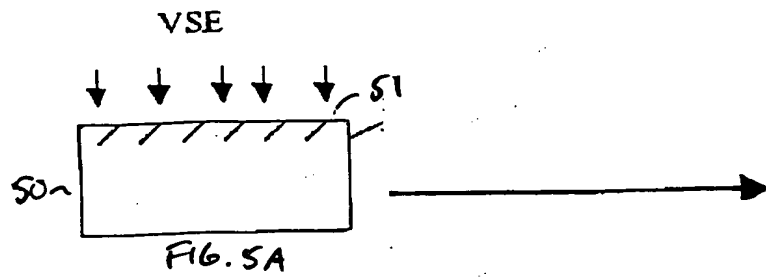


FIG. 3E





Plasma Treatment Effect

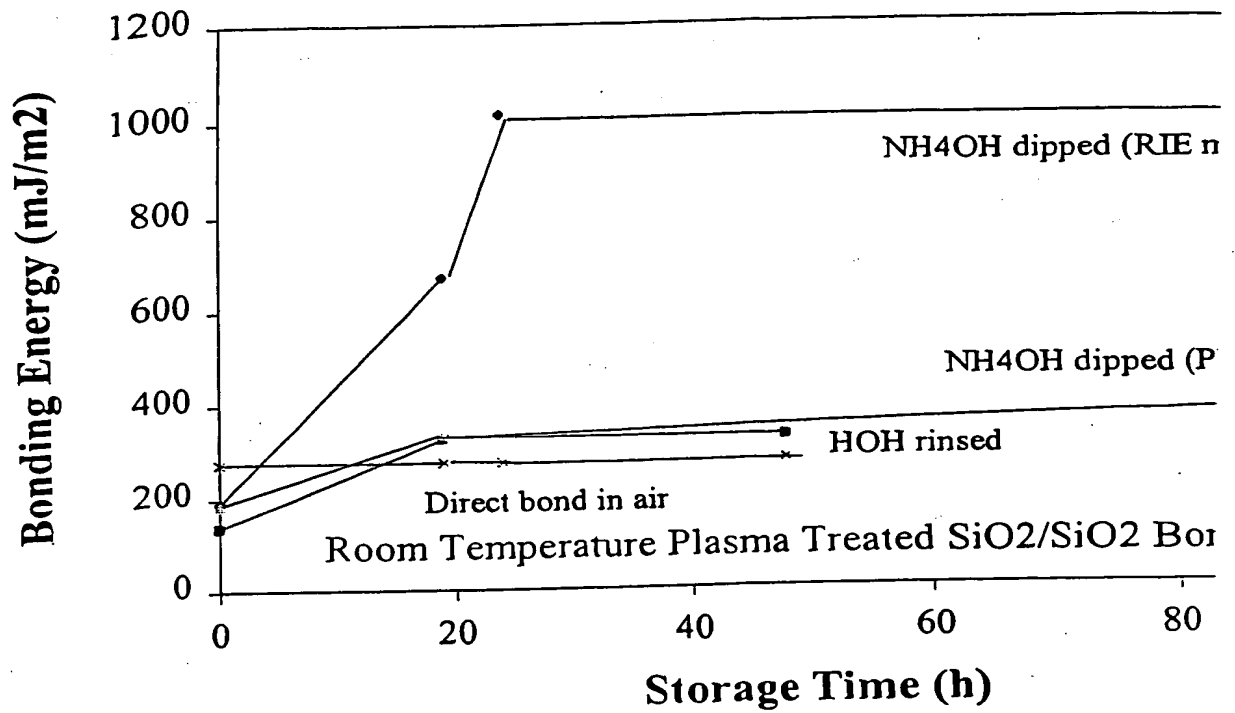


FIG. 6A

Room Temperature Si/AlN Bonding

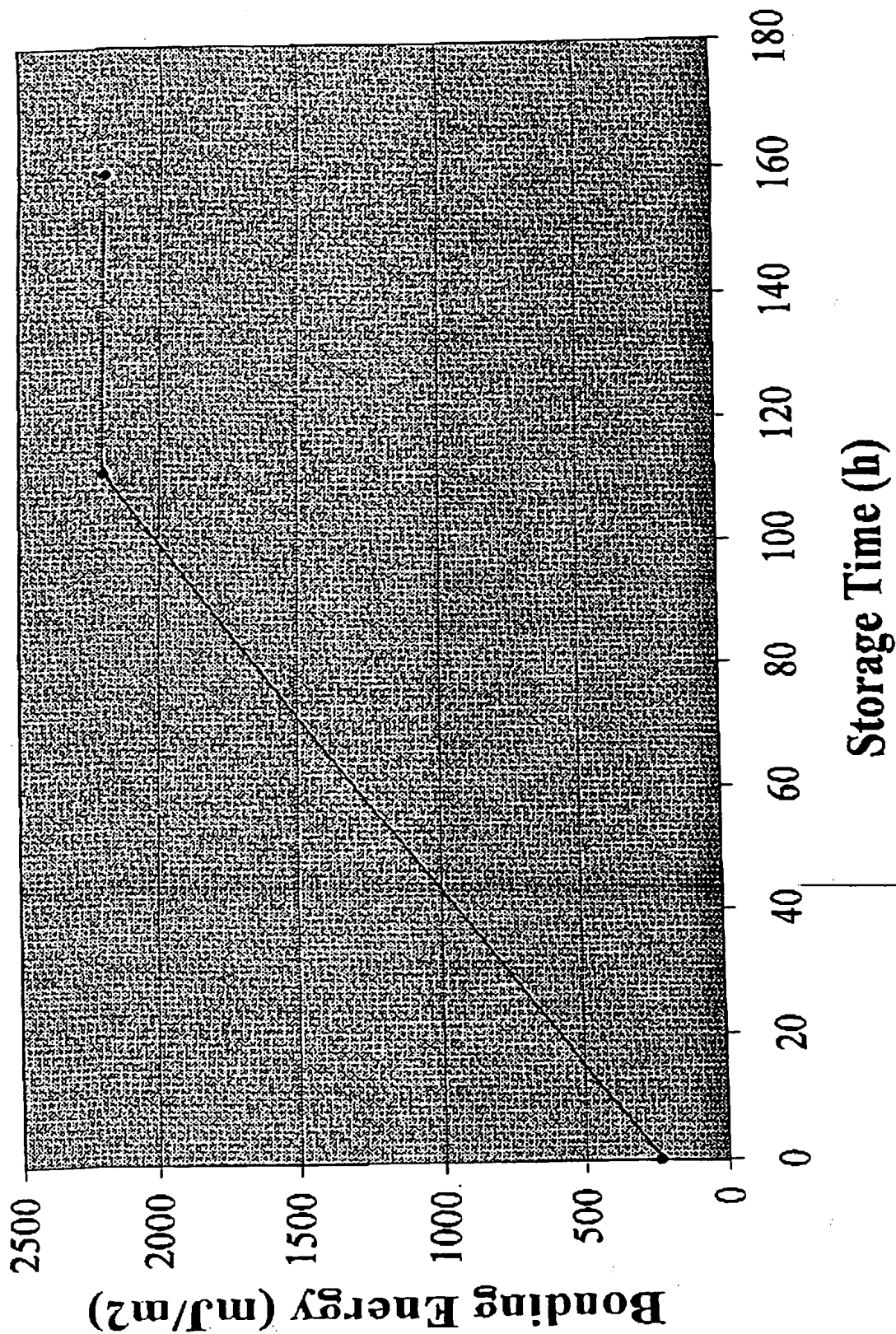


FIG. 6B

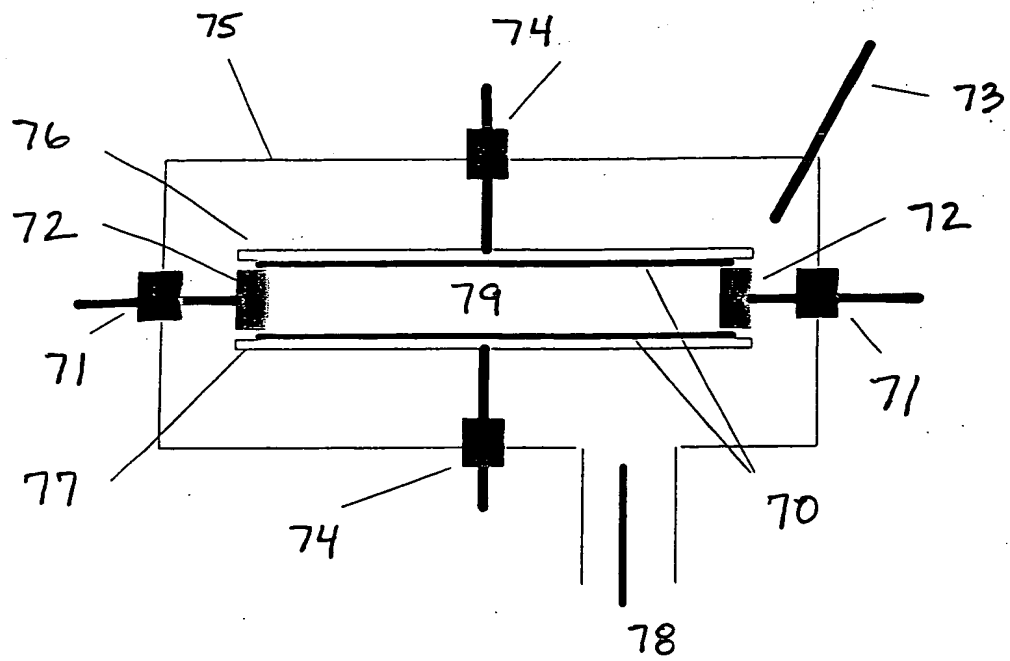
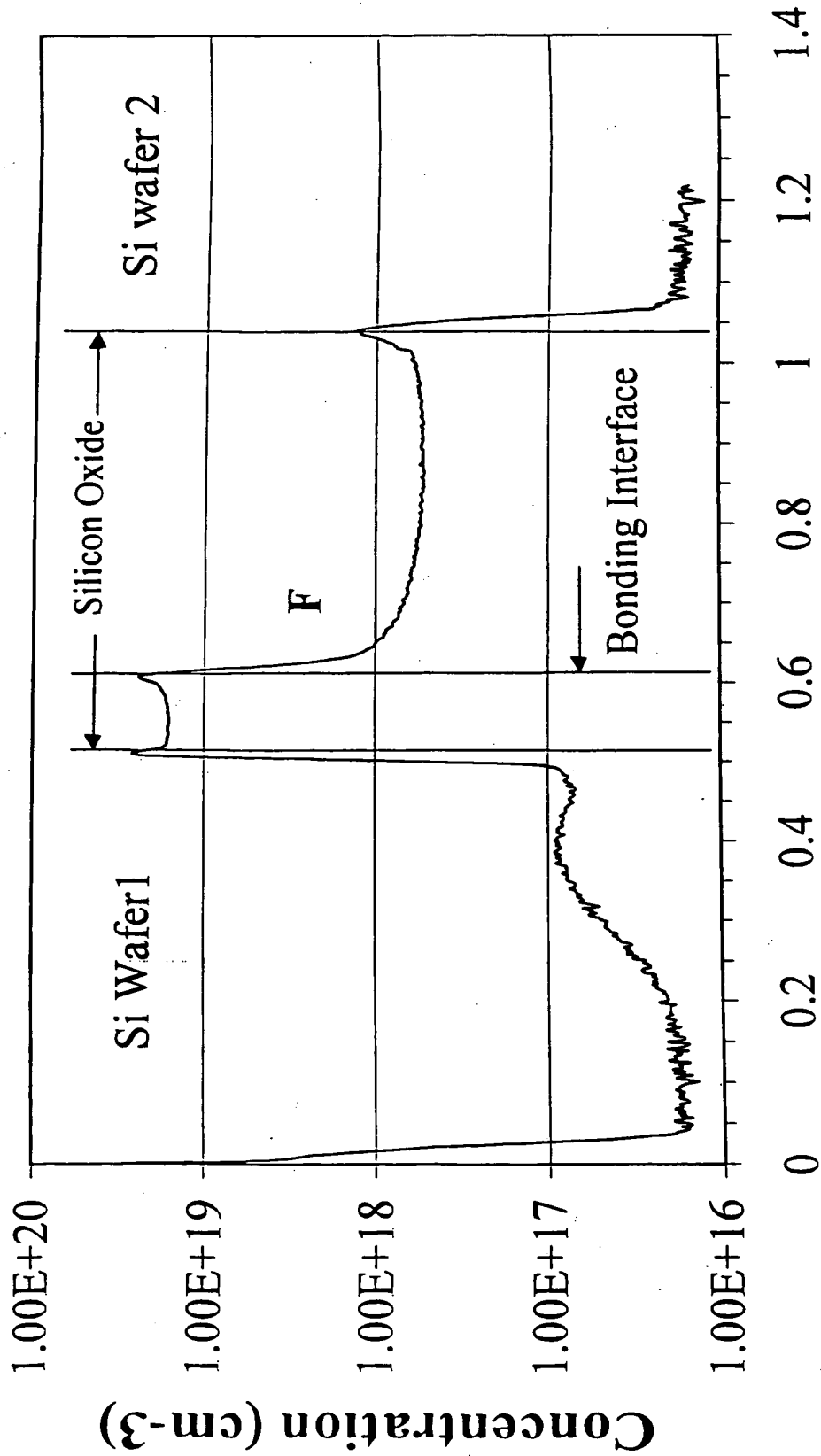


FIG. 7

SIMS Fluorine Profile



Distance from Si surface (micron)

FIG. 8